

# EAST Search History

10/781,369

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	262423	method near (prob\$4 or contact\$4 or test\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/03 13:41
L2	188128	1 and (semiconductor\$1 or integrated adj circuit\$1 or ic\$1 or die\$1 or dice\$1 or component\$1)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/03 13:42
L3	106303	2 and (position\$4 or movement)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/03 13:43
L4	34273	3 and align\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/03 13:44
L5	23015	4 and (x\$1y or parallel or horizontal)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/03 13:47
L6	702	5 and vertical near movement	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/03 13:47
L7	639	4 and ((x\$1y or parallel or horizontal) near movement)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/03 13:47
L8	126	7 and vertical near movement	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/03 13:47